

# INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

WFS.006 CIP

Application Number

~~NEW~~ 10/828,550

Applicant(s)

Daniel R. NEAL et al.

Filing Date

21 April 2004

Group Art Unit

TBD 2873

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/JS/	A	6,199,986	03/13/2001	Williams et al.			
	B	6,299,311 B1	10/09/2001	Williams et al.			
	C	4,725,138	02/16/1988	Wirth et al.			
	D	5,978,053	11/02/1999	Giles et al.			
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	F	6,270,221 B1	08/07/2001	Liang et al.			
	G	5,258,791	11/02/1993	Penney et al.			
	H	4,021,102	05/03/1977	Iizuka			
	I	3,819,256	06/25/1974	Bellows et al.			
	J	5,929,970	07/27/1999	Mihashi			
/JS/	K	6,271,915 B1	08/07/2001	Frey et al.			

## FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
/JS/	L	0 625 332 A2	11/23/1994	European Patent Office			✓	
	M	DE 42 22 395 A1	01/13/1994	Germany				✓
	N	0 373 788 A2	06/20/1990	European Patent Office			✓	
	O	WO 83/02716	08/18/1983	PCT				✓
/JS/	P	WO 01/89372 A2	11/29/2001	PCT			✓	

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/JS/	Q	Geary, Joseph M., Introduction to Wavefront Sensors, SPIE Press, Vol. TT18, copyright 1995, pages 93-95.

EXAMINER

/Jessica Stultz/

DATE CONSIDERED

09/28/2007

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Applicant(s) Daniel R. NEAL, et al.	
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[illegible][illegible]

/JS/	u	International Search Report printed November 26, 2001, pages 1 and 2.

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SHEET 2 OF 4

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10/828,550

Applicant(s)

Daniel R. Neal et al.

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21 April 2004

Group Art Unit

2873

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/JS/	A	US-6,394,605 B1	5/28/2002	Campin et al.			
	B	US-6,382,795 B1	5/7/2002	Lai, Ming			
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							YES	NO
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/JS/	H	Brown, et al.; Measurement of the dynamic deformation of a high frequency scanning mirror using a Shack-Hartmann wavefront sensor; SPIE's 46th Annual Meeting International Symposium on Optical Science and Technology 29 July - 3 August 2001; pages 1-9.
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Applicant(s) <b>Daniel R. Neal et al.</b>		
Filing Date <b>21 April 2004</b>	Group Art Unit <b>TBD 2873</b>	

EXAMINER INITIAL	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)
/JS/	J Daniel R. Neal et al.; Application of Shack-Hartmann Wavefront Sensors to Optical System Calibration and Alignment; pages 234-240.
	K Daniel R. Neal et al.; Characterization of Infrared Laser Systems; SPIE 3437-05 (1998); pages 1-11.
	L Daniel R. Neal et al.; Amplitude and phase beam characterization using a two-dimensional wavefront sensor; SPIE Vol. 2870, 0-8194-2267-3/96; pages 72-82.
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	Q Platt et al.; History and Principles of Shack-Hartmann Wavefront Sensing; Journal of Refractive Surgery, Volume 17, September/October 2001; pages S573-S577.
	R Lindlein, et al.; Experimental results for expanding the dynamic range of a Shack-Hartmann sensor using astigmatic microlenses; Optical Engineering, Vol. 41 No. 2, February 2002; pages 529-533.
	S Lindlein et al.; Absolute sphericity measurement: a comparative study of the use of interferometry and a Shack-Hartmann sensor; Optics Letters / Vol. 23, No. 10 / May 15, 1998; pages 742-744.
/JS/	T Lindlein et al.; Dynamic range expansion of a Shack-Hartmann sensor by use of a modified unwrapping algorithm; Optics Letters / Vol. 23, No. 13 / July 1, 1998; pages 995-997.
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